Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,026	YARDMAN, JOSEPH	
Examiner	Art Unit	
DANH C. LE	2683	

SEARCHED					
Class	Subclass	Date	Examiner		
455	456,4	8 15 05	DCL		
	456.4 456.1				
	575.1				
340	686.6				
	686.6				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	· EXMR		
Inventor Name Search (For double Patent check)	8 15 05	DCL		
(For dowble latent check)				
Lee Nguyen (455)				
Hun Vilong (455)				
	·	*		
EAST Search	8 16 05	DCL		
(USP, USPUB, JPU, EPO, DERWENT)				
Interference Search				